

RELIABILITY MONITOR REPORT
FOR

0.35 μ m Chartered Process

Dallas Semiconductor

4401 South Beltwood Parkway
Dallas, TX 75244-3292

This Report was prepared by
Dallas Semiconductor Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The products covered by this process monitor are:

DS21455	DS21458	DS2155	DS2156	DS2174
DS2194	DS21FF42	DS21FF44	DS21FT42	DS21FT44
DS21Q42	DS21Q44	DS26101	DS26102	DS26303
DS26324	DS26334	DS26401	DS26502	DS26503
DS26504	DS26521	DS26522	DS26524	DS26528
DS26556	DS3112	DS31256	DS3131	DS3134
DS3141	DS31412	DS3142	DS3143	DS3144
DS3146	DS3148	DS3150	DS3151	DS3152
DS3153	DS3154	DS3160	DS3161	DS3162
DS3163	DS3164	DS3170	DS3171	DS3172
DS3173	DS3174	DS3181	DS3182	DS3183
DS3184	DS3251	DS3252	DS3253	DS3254
DS33R11	DS33R41			

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 65685 FITS: 1.7

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows. At the start of this data is the process information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available. This report covers data between 4/1/2006 and 3/31/2007 .

Device Information:

Process: 0.35 µm Chartered Process
 Interconnect: Aluminum / 1% Silicon / 0.5% Copper
 Gate Oxide Thickness: 75 Å

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	0611	DS3112	125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0614	DS26401	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0616	DS26401	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0616	DS26401	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0616	DS26401	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0618	DS2155	125C, 3.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0619	DS31256	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0620	DS26528	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0632	DS26334	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0632	DS26303	125C, 3.5 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0641	DS3254	125C, 3.5 VOLTS	1000 HRS	45	0	
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
STORAGE LIFE	0611	DS3112	150C	1000 HRS	77	0	
STORAGE LIFE	0614	DS26401	150C	1000 HRS	77	0	
STORAGE LIFE	0616	DS26401	150C	1000 HRS	77	0	
STORAGE LIFE	0616	DS26401	150C	1000 HRS	77	0	
STORAGE LIFE	0616	DS26401	150C	1000 HRS	77	0	
STORAGE LIFE	0619	DS31256	150C	1000 HRS	107	0	
				Total:		0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
TEMP CYCLE	0611	DS3112	-55C TO 125C	1000 CYS	77	0	
TEMP CYCLE	0614	DS26401	-55C TO 125C	1000 CYS	77	0	
TEMP CYCLE	0616	DS26401	-55C TO 125C	1000 CYS	77	0	
TEMP CYCLE	0616	DS26401	-55C TO 125C	1000 CYS	77	0	
TEMP CYCLE	0616	DS26401	-55C TO 125C	1000 CYS	77	0	
TEMP CYCLE	0619	DS31256	-55C TO 125C	1000 CYS	77	0	
				Total:		0	

TEMPERATURE HUMIDITY BIAS

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
BIASED MOISTURE	0611	DS3112	85/85, 3.5 VOLTS	1000 HRS	45	0	
BIASED MOISTURE	0616	DS26401	85/85, 3.5 VOLTS	1000 HRS	45	0	
BIASED MOISTURE	0616	DS26401	85/85, 3.5 VOLTS	1000 HRS	45	0	
BIASED MOISTURE	0616	DS26401	85/85, 3.5 VOLTS	1000 HRS	45	0	
BIASED MOISTURE	0619	DS31256	85/85, 3.5 VOLTS	1000 HRS	45	0	
				Total:		0	

UNBIASED MOISTURE RESISTANCE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HAST, NO BIAS	0616	DS26401	130C, 85% R.H.	200 HRS	77	0	
HAST, NO BIAS	0616	DS26401	130C, 85% R.H.	200 HRS	73	0	
HAST, NO BIAS	0616	DS26401	130C, 85% R.H.	200 HRS	70	0	
				Total:		0	

FAILURE RATE:**MTTF (YRS): 65685****FITS: 1.7**